

**30V, 30A DUAL N-CHANNEL POWER MOSFET**

**GENERAL DESCRIPTION**

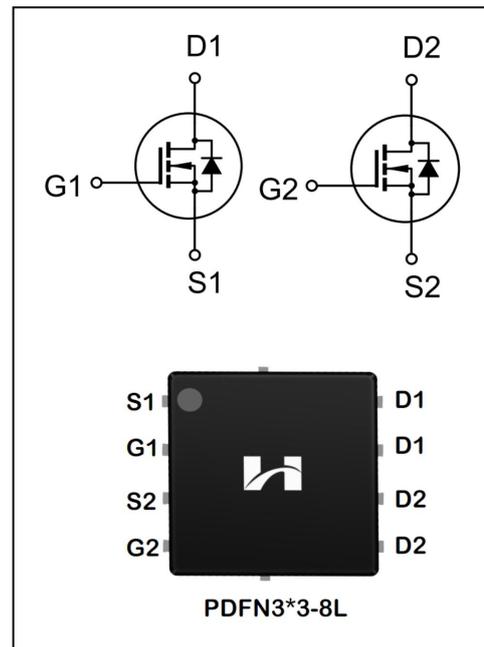
The SFN0330T2 uses advanced trench technology and design to provide excellent  $R_{DS(on)}$  with low gate charge. It can be used in a wide variety applications.

**Features**

- ◆  $V_{DS}=30V, I_D=30A$
- ◆  $R_{DS(on)}$   
TYP:  $8.3m\Omega @ V_{GS}=10V$

**Applications**

- ◆ Power faction correction (PFC)
- ◆ Switched mode power supplies (SMPS)
- ◆ Uninterruptible power supply (UPS)
- ◆ LED lighting power



**ORDERING INFORMATION**

Part No.	Package	Marking	Material	Packing
SFN0330T2	PDFN3*3-8L	SFN0330T2	Pb Free	Reel

**ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)**

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		V <sub>DS</sub>	30	V
Gate-Source Voltage		V <sub>GS</sub>	±20	V
Drain Current	T <sub>C</sub> = 25°C	I <sub>D</sub>	30	A
	T <sub>C</sub> = 100°C		21.5	
Drain Current Pulsed(Note 1)		I <sub>DM</sub>	120	A
Power Dissipation(T <sub>C</sub> =25°C) -Derate above 25°C		P <sub>D</sub>	32	W
Single Pulsed Avalanche Energy (Note 2)		E <sub>AS</sub>	81	mJ
Operation Junction Temperature Range		T <sub>J</sub>	-55~+150	°C
Storage Temperature Range		T <sub>stg</sub>	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		TL	300	°C

**THERMAL CHARACTERISTICS**

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	4.15	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	43.5	°C/W

**ELECTRICAL CHARACTERISTICS**

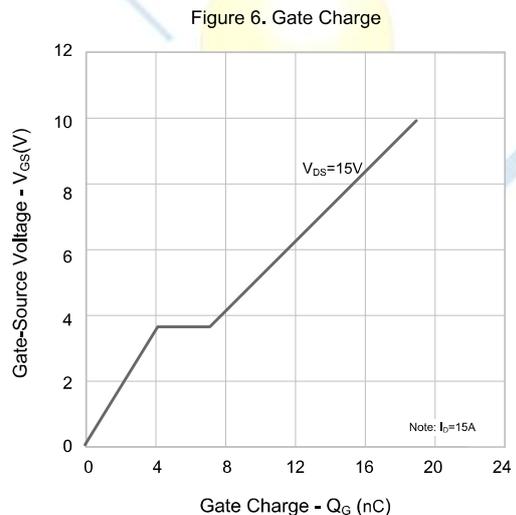
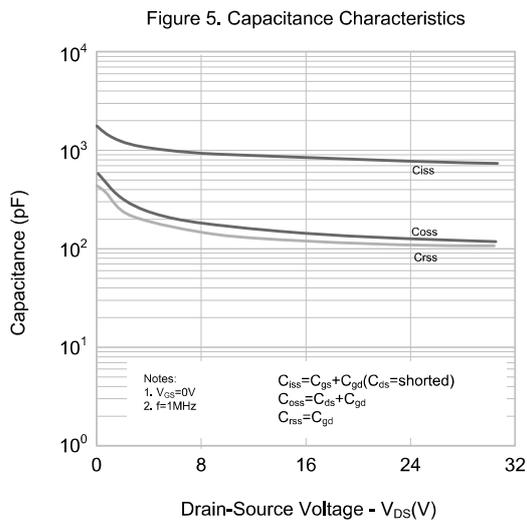
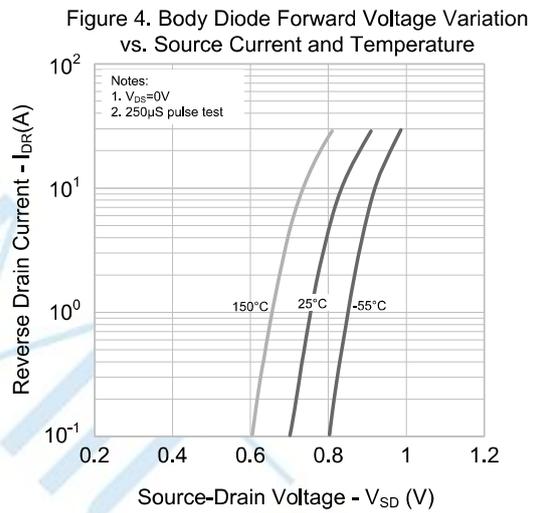
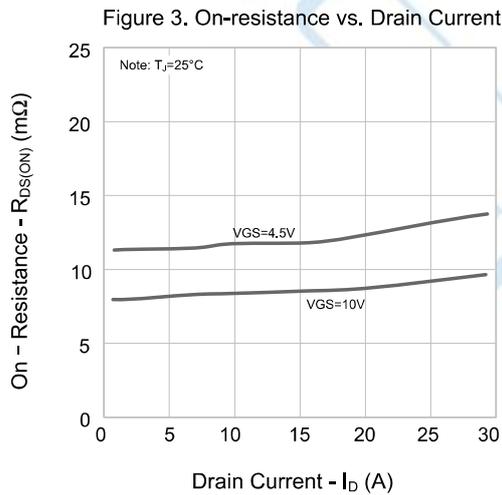
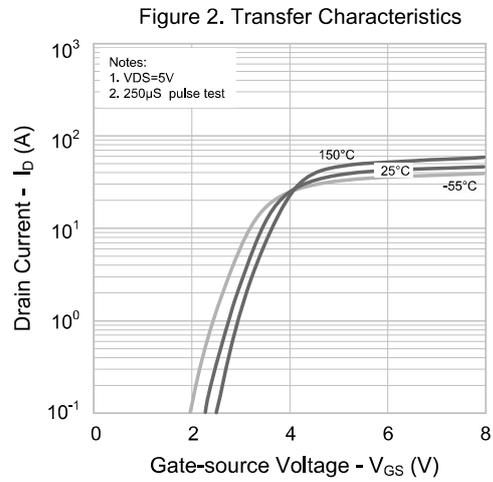
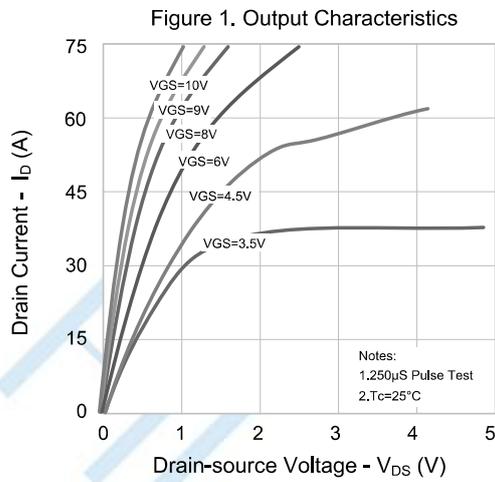
Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
Drain -Source Breakdown Voltage	B <sub>VDS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	30	--	--	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V	--	--	1	uA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	--	--	-100	
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	1.2	1.45	1.8	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =15A	--	8.3	10.5	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A	--	12.0	16.5	
<b>Dynamic Characteristics</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =15V V <sub>GS</sub> =0V f=1.0MHZ	--	853	--	pF
Output Capacitance	C <sub>oss</sub>		--	165	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	130	--	
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =15V, R <sub>G</sub> =10Ω I <sub>D</sub> =15A (Note 3.4)	--	7.3	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	6.2	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	25.6	--	
Turn-off Fall Time	t <sub>f</sub>		--	8.5	--	
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =15V, I <sub>D</sub> =15A V <sub>GS</sub> =10V (Note 3.4)	--	18.1	--	nc
Gate-Source Charge	Q <sub>gs</sub>		--	5.3	--	
Gate-Drain Charge	Q <sub>gd</sub>		--	6.5	--	

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

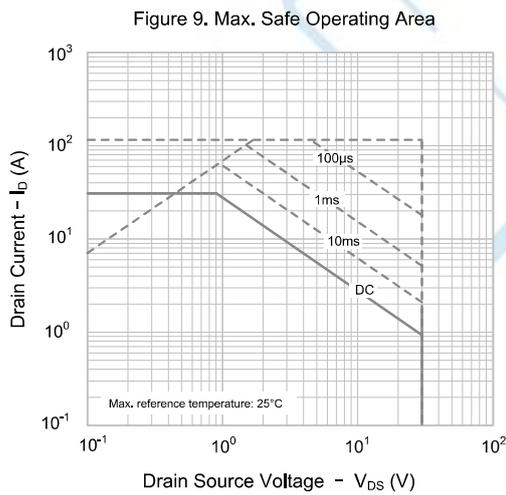
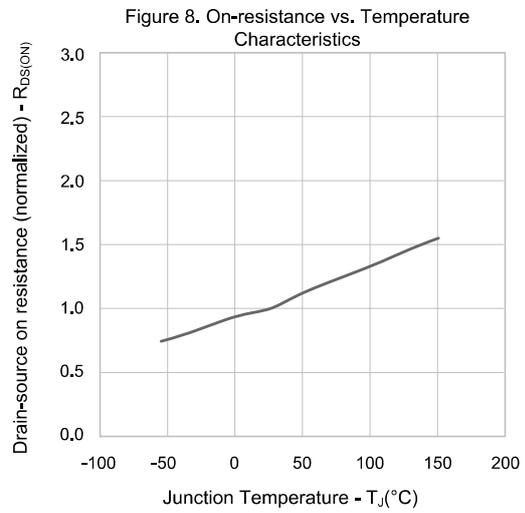
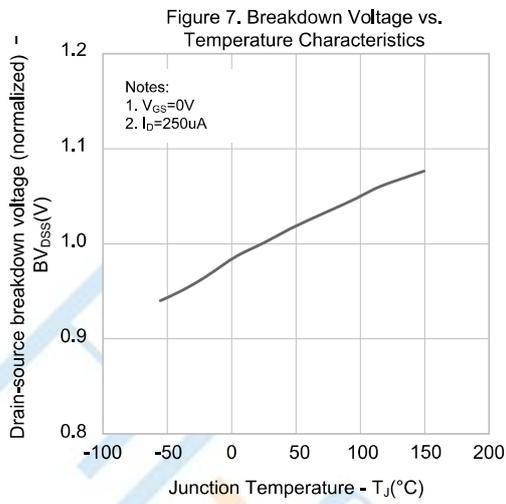
Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_S$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	30	A
Pulsed Source Current	$I_{SM}$		--	--	120	
Diode Forward Voltage	$V_{SD}$	$I_S=15A, V_{GS}=0V$	--	0.83	1.2	V
Reverse Recovery Time	$T_{rr}$	$I_F=15A$ $dI_F/dt=100A/\mu S$	--	18.3	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	11	--	nC

1. Pulse width limited by maximum junction temperature
2.  $L=0.5mH$ ,  $V_{DD}=20V$ ,  $V_G=10V$ ,  $R_G=25\Omega$ , starting  $T_J=25^\circ C$
3. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$
4. Essentially independent of operating temperature

Typical Performance Characteristics

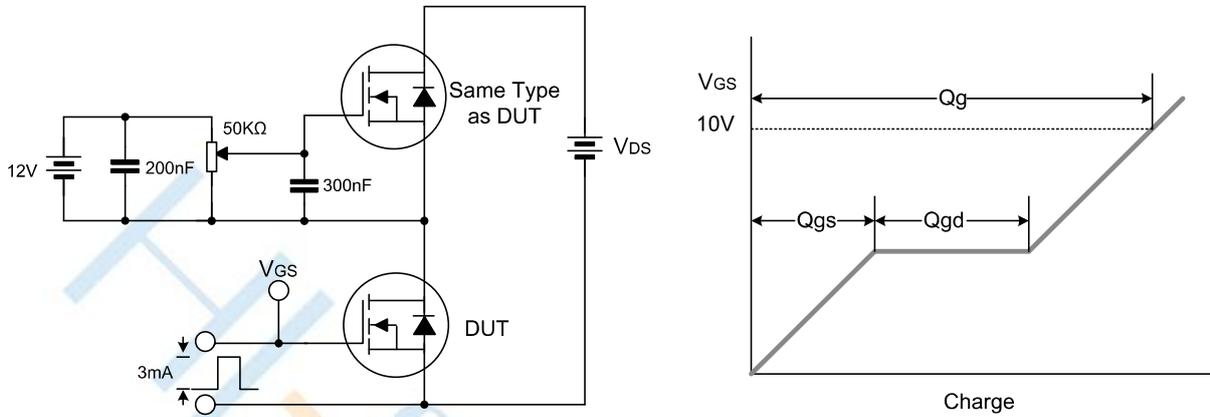


Typical Performance Characteristics

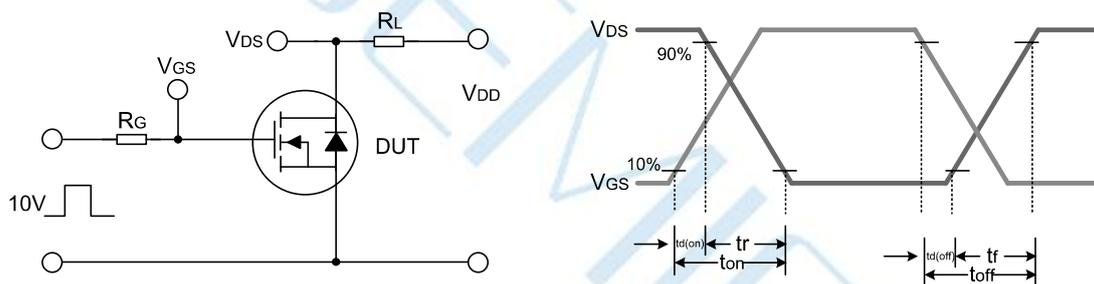


Test Circuit

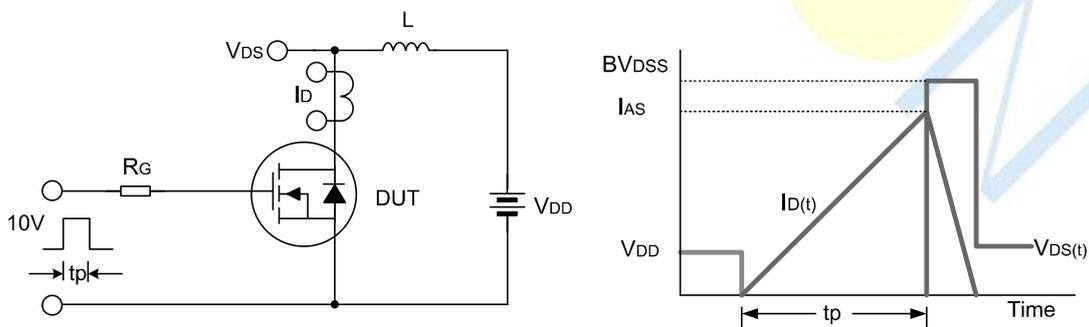
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform

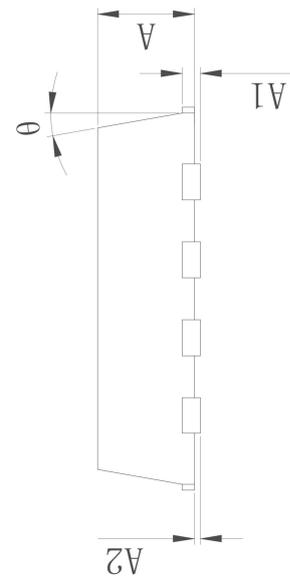
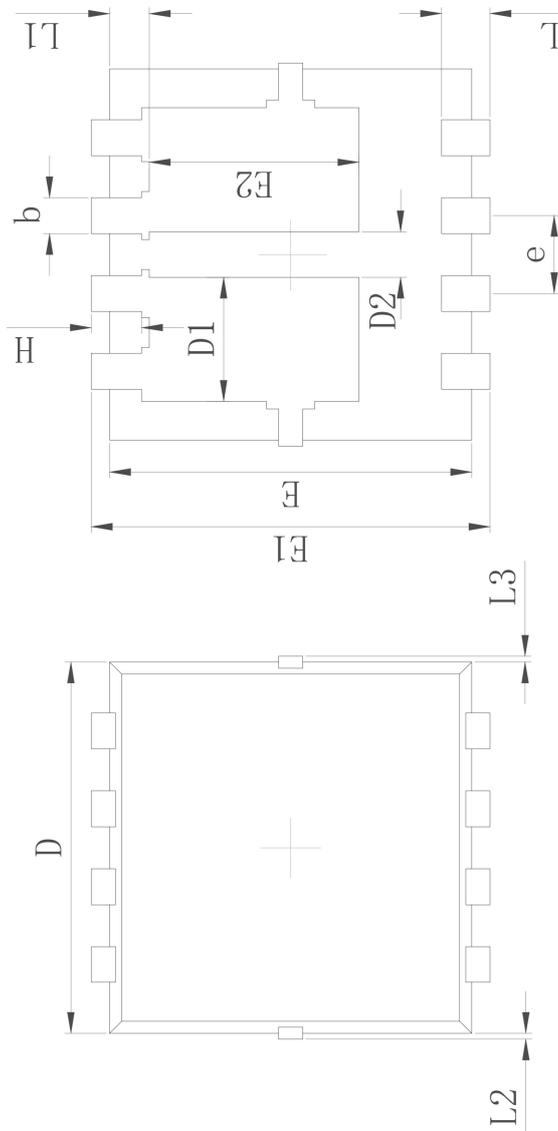


Undamped Inductive Switching Test Circuit & Waveform



Package Dimensions of PDFN3\*3-8L

SYMBOL	MILLIMETER	
	MIN	MAX
A	0.700	0.900
A1	0.152 REF.	
A2	0 <sup>~</sup> 0.05	
D	3.000	3.200
D1	0.935	1.135
D2	0.280	0.480
E	2.900	3.100
E1	3.150	3.450
E2	1.535	1.935
b	0.200	0.400
e	0.550	0.750
L	0.300	0.500
L1	0.180	0.480
L2	0 <sup>~</sup> 0.100	
L3	0 <sup>~</sup> 0.100	
H	0.315	0.515
θ	8°	12°



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